Search Notes (continued)



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/696,203	HANSON ET AL.	
Examiner	Art Unit	
Sun J Lin	2825	

 	SEAR	CHED					
Class	Subclass	Date	Examiner				
716	19	6/6/2006	JSL				
716	21	6/6/2006	JSL				
716	1	6/6/2006	JSL				
716	2	6/6/2006	JSL				
716	4	6/6/2006	JSL				

INT	ERFEREN	RFERENCE SEARCHED			
Class	Subclass	Date	Examiner		
716	1,2,4	6/6/2006	JSL		
716	19	6/6/2006	JSL		
716	21	6/6/2006	JSL		

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	6/6/2006	JSL
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